

Interaction hydrogen plasma and a-Si:H thin film

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Hydrogen role

Processing aspects

Fundamental role in a-Si:H and $\mu\text{c-Si:H}$ deposition, etching, surface passivation, chemical annealing,...

In solar cells

Hydrogen affects the SnO_2 , the P-layer, and the P/I interface.

In-situ study of hydrogen diffusion in a-Si:H by SE

- a-Si:H is deposited by **PECVD**
- Reactor **CAMELEON**
- In-situ measurements by **UV-visible ellipsometry**
- Ex-situ measurements by **SIMS**

Effects of hydrogen plasma

Etching

Clean walls

PECVD, HWCVD,

H

SiH₄

a-Si:H

Substrate

Chemical transport

a-Si:H coated walls

PECVD, HWCVD,

SiH₄

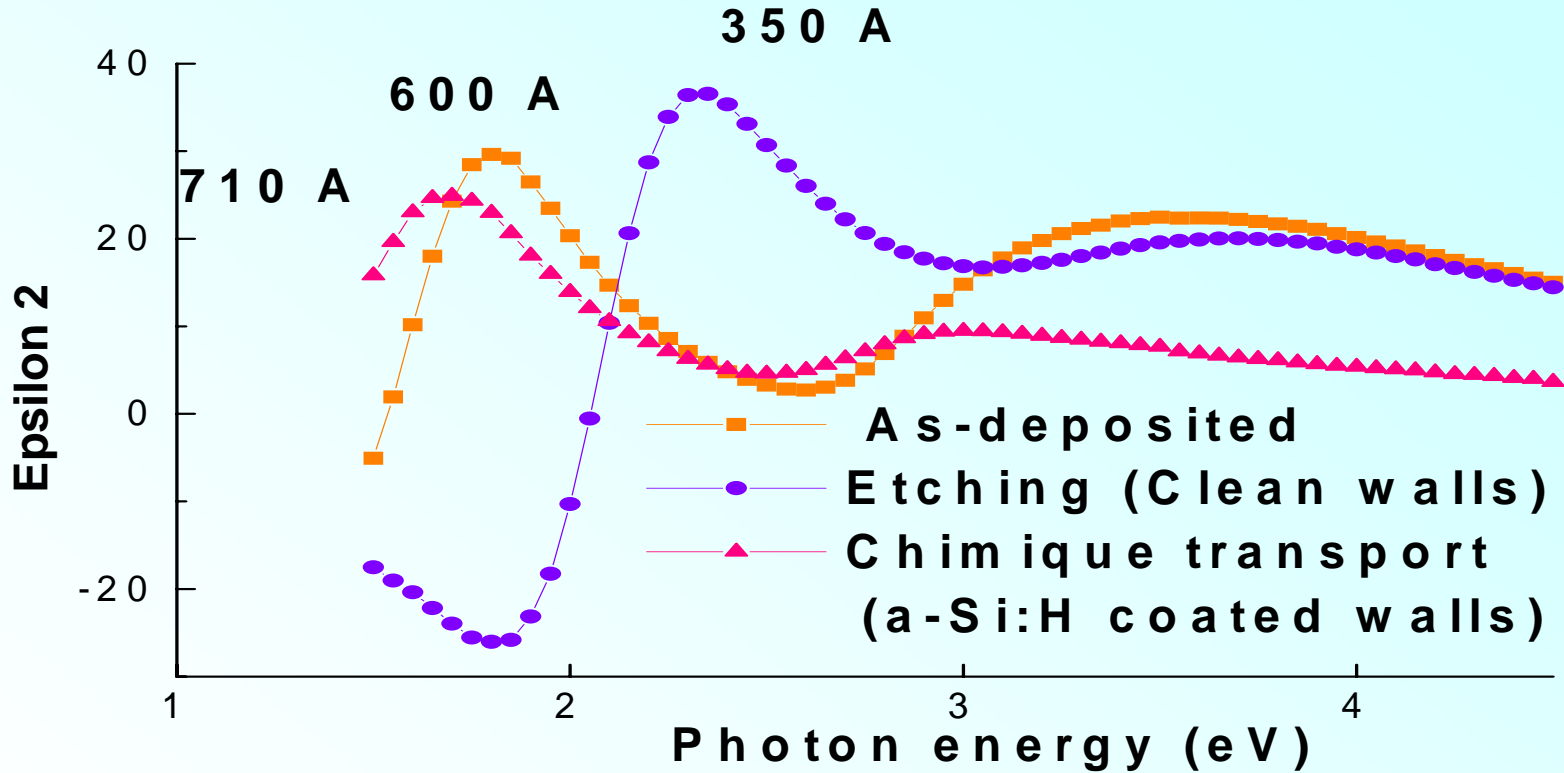
H

SiH₃

Substrate

N-type a-Si:H exposed for 10 minutes to a hydrogen plasma

250 sccm, 1 torr, 250°C, 30W



The Shift of interference fringes

High energy

Etching

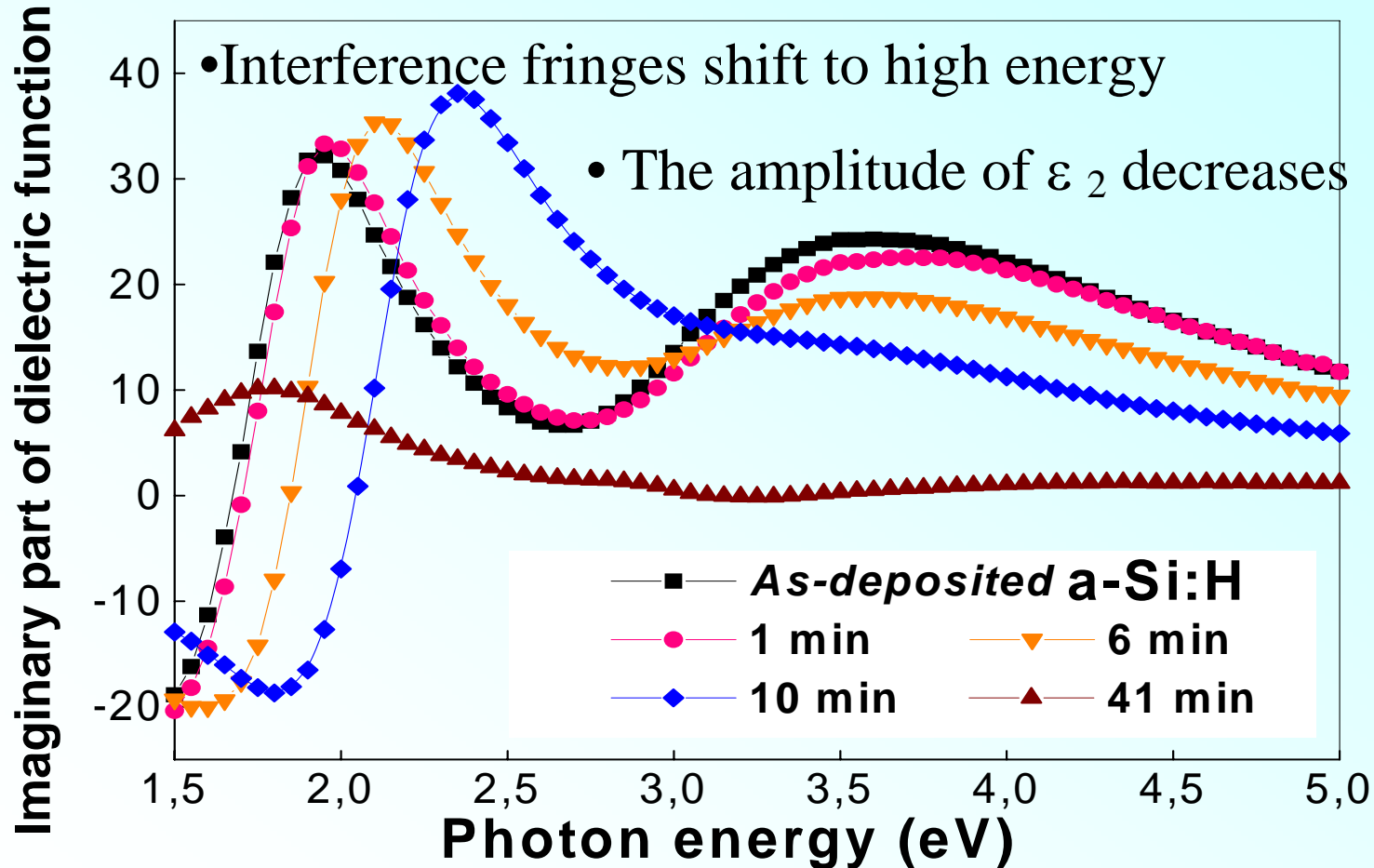
Low energy

Chemical transport

I. Etching of Intrinsic a-Si:H

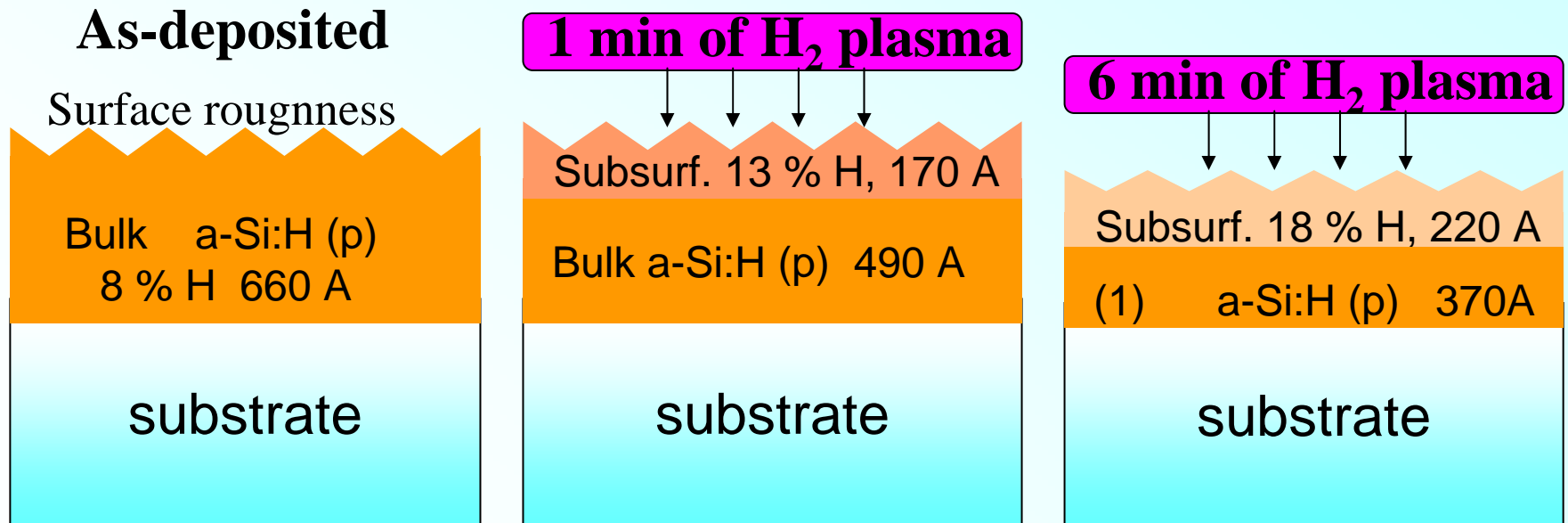
a-Si:H deposition : $P = 60$ mtorr, $P_{rf} = 3$ W, $T_s = 230^\circ\text{C}$.

H_2 Plasma : $P = 1$ torr, $P_{rf} = 22$ W, $T_s = 230^\circ\text{C}$.

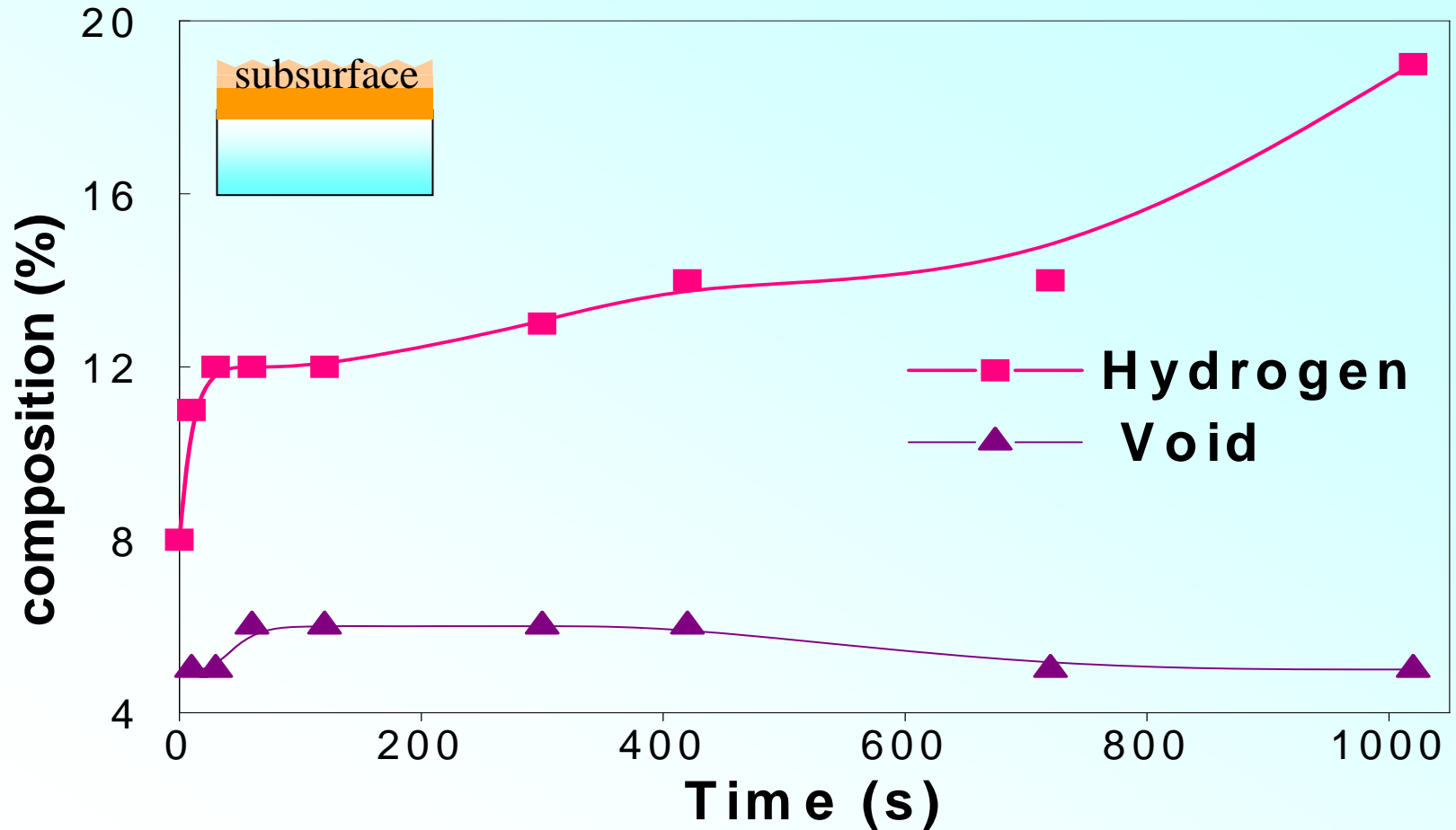


Optical Model

1. Tauc's Lorentz model to analyze the a-Si:H substrate
2. Tetrahedron model to take into account the effect of hydrogen
3. BEMA: the dielectric function of the material exposed to hydrogen is described as a mixture of the initial a-Si:H, plus voids, plus Si-Si₃H



Analysis of the SE data on a-Si:H

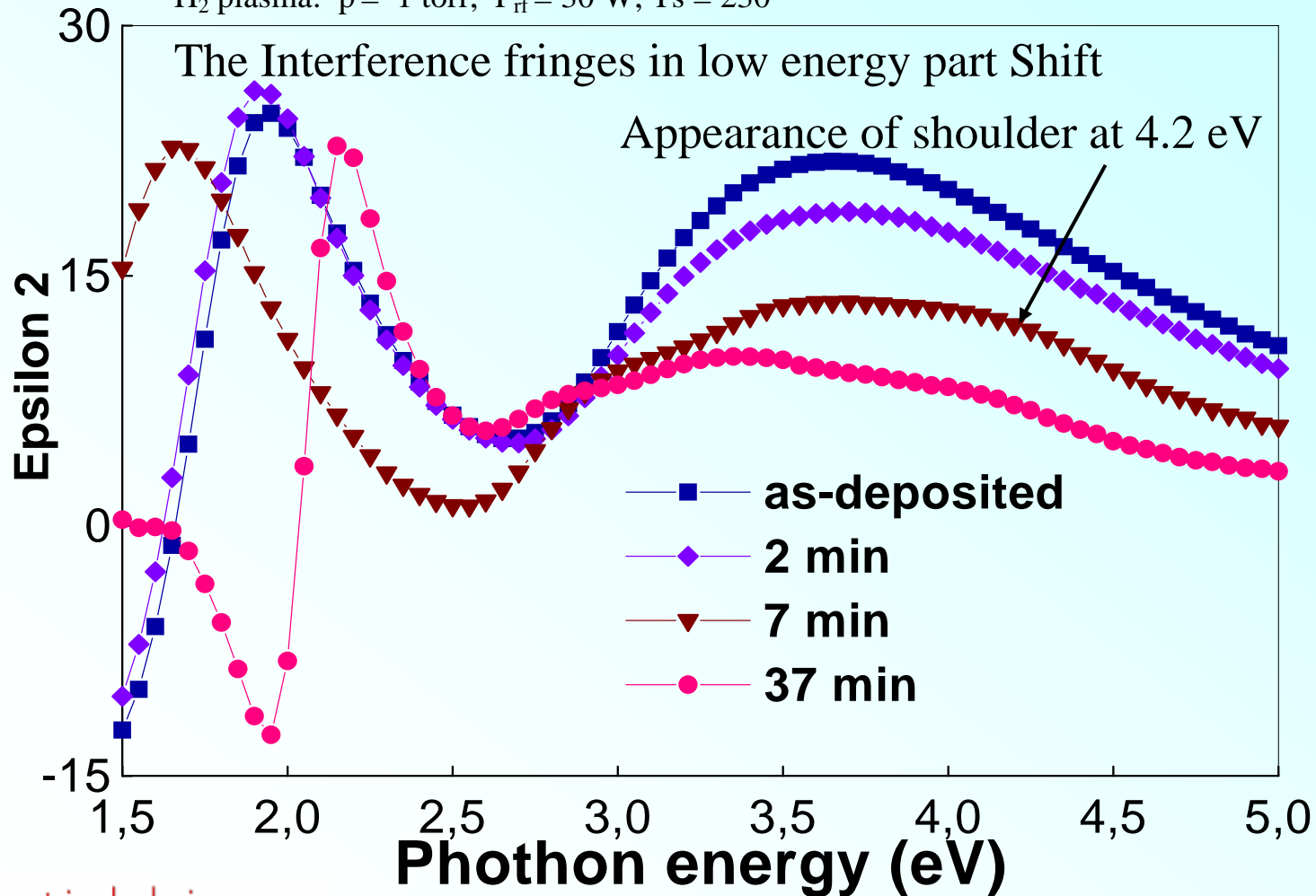


II. Chemical transport in a-Si:H

S.Veprek, al, J. Phys; C 14 (1968)

a-Si:H deposition : $p = 60$ mtorr, $P_{rf} = 5$ W, $T = 230^\circ\text{C}$.

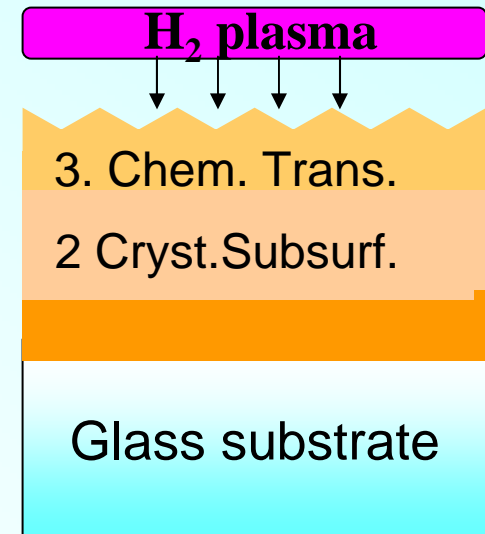
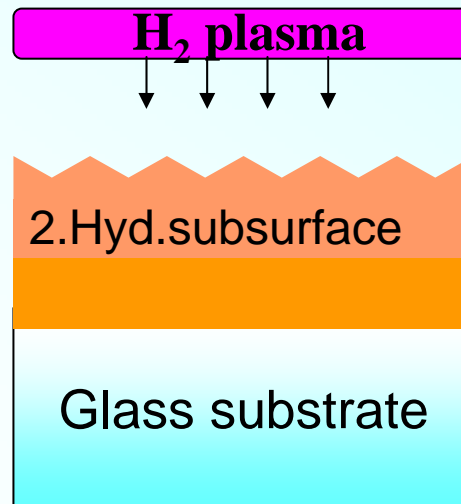
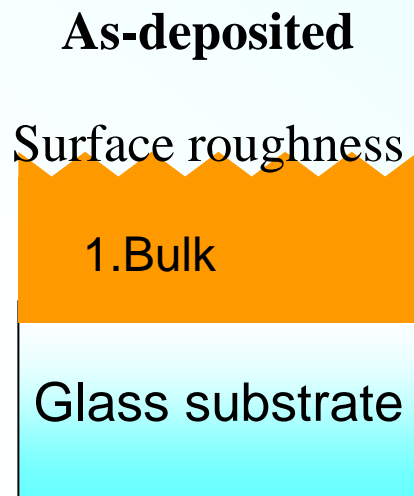
H_2 plasma: $p = 1$ torr, $P_{rf} = 30$ W, $T_s = 230^\circ$



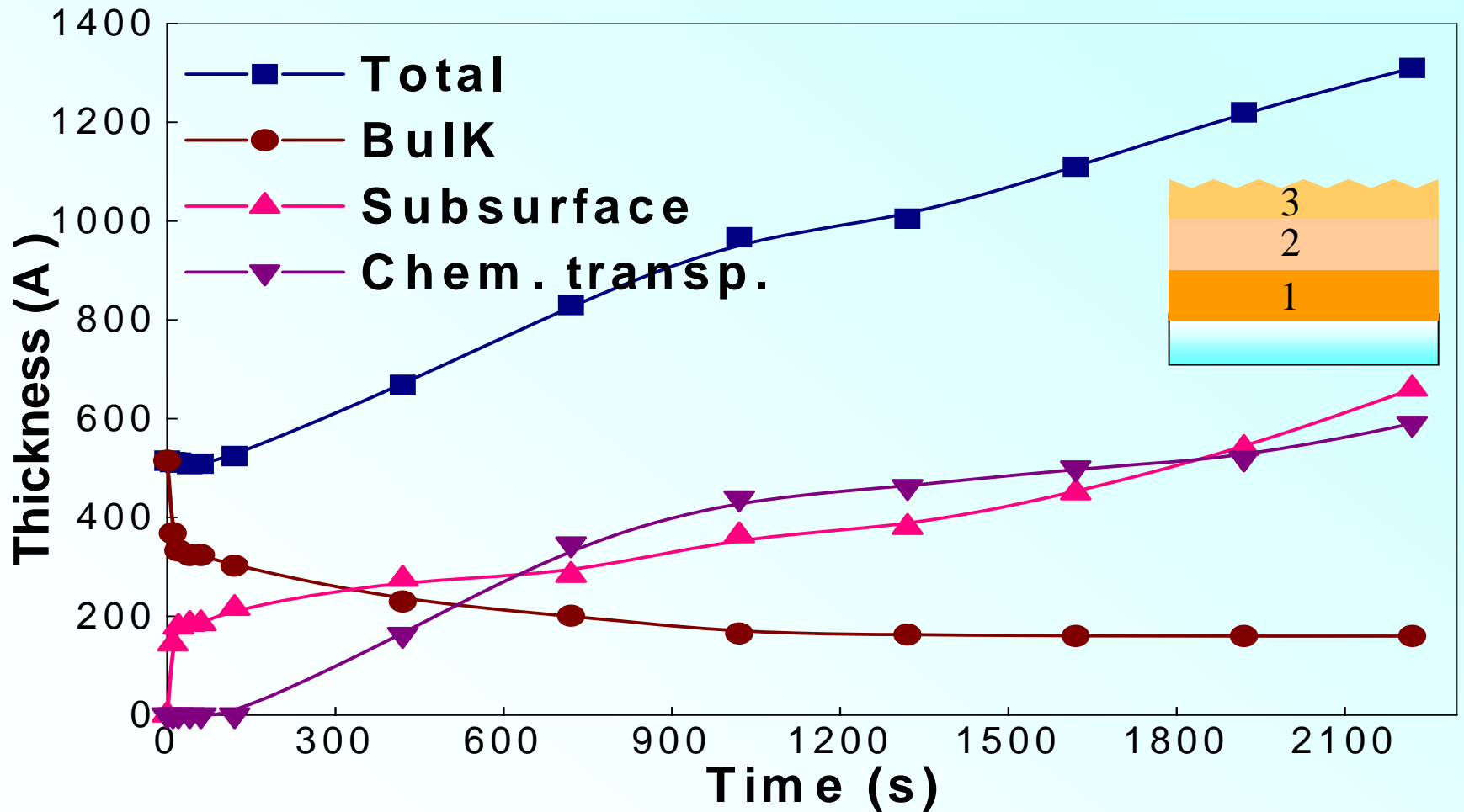
Optical Model

Bruggeman Effective Medium Approximation (B.E.M.A)

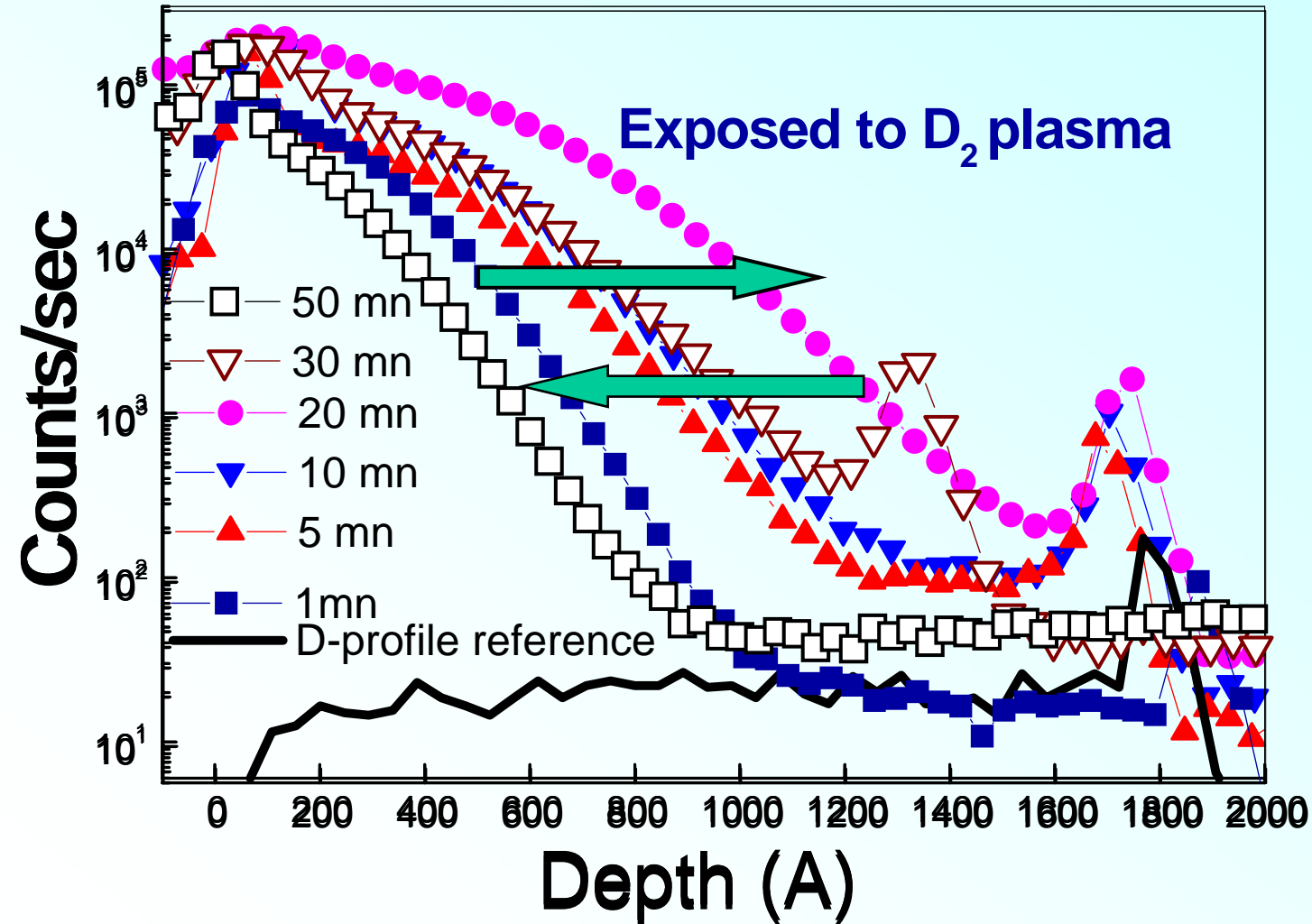
0. Roughness: Amorphous (Aspnes) + Void
1. Bulk: Amorphous (Aspnes) + Void
2. Subsurface layer : Amorphous + Void + μ c cristallin
3. Chemical Transport Layer : Amorphous + Void + μ -cristallin



Analysis of the SE data in Intrinsic a-Si:H



III. Results: SIMS measurements Deuterium profiles

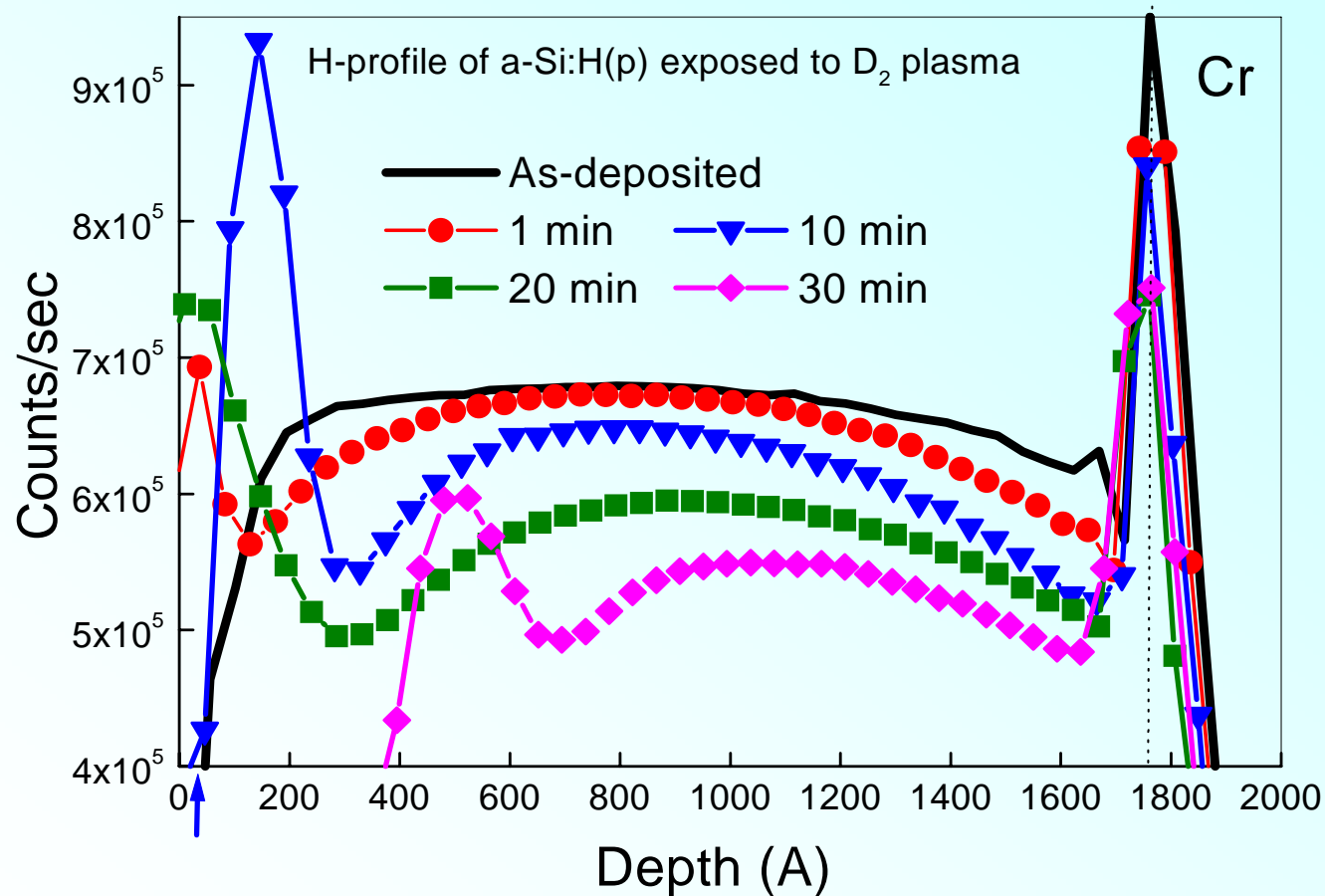


*D diffuses to
the back of
the sample*

*Afterwards to
the crystallized
region !*

III. Results: SIMS measurements

Hydrogen profiles



Hydrogen moves towards the crystallization region
Once the crystallization starts, H-accumulation decreases

IV. Summary and Conclusion

- *Hydrogen plasma exposure of a-Si:H films starts by the **formation of a hydrogen rich subsurface layer***

- *This process leads to:*

***Etching** when hydrogen is alone in plasma (clean walls)*

***Deposition of μ c-Si:H film** by chemical transport when the walls are a-Si:H coated walls*

IV. Summary and Conclusion

*Once a microcrystalline silicon film is formed, **both deuterium and Hydrogen move towards the surface** and are removed from the sample*

WHY ?

Heterojunction effect ?

Your suggestions are welcome !